New Trends on Pattern Recognition and Computer Vision, Applications and Systems

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Deadline for manuscript submissions:
closed (28 November 2021)

Message from the Guest Editors

The New Trends on Pattern Recognition and Computer Vision , Applications and Systems special issue aims to collect the latest approaches and findings, as well as to discuss the current challenges of Pattern recognition solutions for a broad range of applications. We expect this special issue addresses the research issues in the closely related areas of Pattern Recognition, such as Machine Learning, Data Mining, Computer Vision and Image Processing.

We welcome high-quality submissions with important new theories, methods, applications, and systems in emerging topics of pattern recognition and computer vision . The topics of interest include, but are not limited to:

- Interpretable Machine Learning for Computer Vision;
- Automated Deep Learning,;
- Zero-shot learning applied to real-world problems;
- Neural Rendering;
- Autonomous Driving;
- Real-time Pattern Recognition applications;

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Special Issue

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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